

FDS3601

100V Dual N-Channel PowerTrench® MOSFET

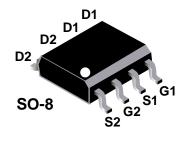
General Description

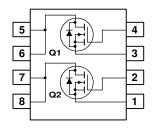
These N-Channel MOSFETs have been designed specifically to improve the overall efficiency of DC/DC converters using either synchronous or conventional switching PWM controllers.

These MOSFETs feature faster switching and lower gate charge than other MOSFETs with comparable $R_{\rm DS(ON)}$ specifications. The result is a MOSFET that is easy and safer to drive (even at very high frequencies), and DC/DC power supply designs with higher overall efficiency.

Features

- 1.3 A, 100 V. $R_{DS(ON)}=480~m\Omega$ @ $V_{GS}=10~V$ $R_{DS(ON)}=530~m\Omega$ @ $V_{GS}=6~V$
- · Fast switching speed
- Low gate charge (3.7nC typical)
- High performance trench technology for extremely low R_{DS(ON)}
- High power and current handling capability





Absolute Maximum Ratings TA=25°C unless otherwise noted

Symbol	Parameter		Ratings	Units
V _{DSS}	Drain-Source Voltage		100	V
V _{GSS}	Gate-Source Voltage		±20	V
I _D	Drain Current - Continuous	(Note 1a)	1.3	А
	- Pulsed		6	
P _D	Power Dissipation for Dual Operation		2	W
	Power Dissipation for Single Operation	(Note 1a)	1.6	
		(Note 1b)	1.0	
		(Note 1c)	0.9	
T _J , T _{STG}	Operating and Storage Junction Temperature Range		-55 to +175	°C

Thermal Characteristics

$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1a)	78	°C/W
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	(Note 1)	40	°C/W

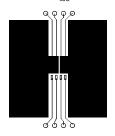
Package Marking and Ordering Information

Device Marking	Device	Reel Size	Tape width	Quantity
FDS3601	FDS3601	13"	12mm	2500 units

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Drain-Sc	ource Avalanche Ratings (Note	2)		ı		I
W _{DSS}	Drain-Source Avalanche Energy	Single Pulse, $V_{DD} = 50 \text{ V}$, $I_D = 1.3 \text{ A}$			26	mJ
I _{AR}	Drain-Source Avalanche Current				1.3	Α
Off Chai	racteristics					
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	100			V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	$I_D = 250 \mu A$, Referenced to $25^{\circ}C$		105		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 80 \text{ V}, \qquad V_{GS} = 0 \text{ V}$			10	μА
I _{GSSF}	Gate-Body Leakage, Forward	$V_{GS} = 20 \text{ V}, \qquad V_{DS} = 0 \text{ V}$			100	nA
I _{GSSR}	Gate-Body Leakage, Reverse	$V_{GS} = -20 \text{ V}, V_{DS} = 0 \text{ V}$			-100	nA
On Char	acteristics (Note 2)					
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$	2	2.6	4	V
$\Delta V_{GS(th)} \over \Delta T_J$	Gate Threshold Voltage Temperature Coefficient	I_D = 250 μ A,Referenced to 25°C		- 5		mV/°C
$R_{\text{DS(on)}}$	Static Drain–Source On–Resistance	$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$		350 376 664	480 530 955	mΩ
I _{D(on)}	On-State Drain Current	$V_{GS} = 10 \text{ V}, \qquad V_{DS} = 10 \text{ V}$	3			Α
g FS	Forward Transconductance	$V_{DS} = 5V$, $I_{D} = 1.3 A$		3.6		S
Dvnami	Characteristics					
C _{iss}	Input Capacitance	$V_{DS} = 50 \text{ V}, \qquad V_{GS} = 0 \text{ V},$		153		pF
Coss	Output Capacitance	f = 1.0 MHz		5		pF
C _{rss}	Reverse Transfer Capacitance			1		pF
Switchir	ng Characteristics (Note 2)					
t _{d(on)}	Turn-On Delay Time	$V_{DD} = 50 \text{ V}, \qquad I_{D} = 1 \text{ A},$		8	16	ns
t _r	Turn-On Rise Time	$V_{GS} = 10 \text{ V}, \qquad R_{GEN} = 6 \Omega$		4	8	ns
t _{d(off)}	Turn-Off Delay Time			11	20	ns
t _f	Turn-Off Fall Time	7		6	12	ns
Qg	Total Gate Charge	$V_{DS} = 50 \text{ V}, \qquad I_{D} = 1.3 \text{ A},$		3.7	5	nC
Q _{gs}	Gate-Source Charge	V _{GS} = 10 V		0.8		nC
Q_{gd}	Gate-Drain Charge			1		nC
Drain-S	ource Diode Characteristics	and Maximum Ratings				
Is	Maximum Continuous Drain-Source				1.3	Α
V _{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = 1.3 \text{ A}$ (Note 2)		0.8	1.2	V

Notes:

1. R_{eJA} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{eJC} is guaranteed by design while R_{eCA} is determined by the user's board design.



78°C/W when mounted on a 0.5in² pad of 2 oz copper



125°C/W when mounted on a 0.02 in² pad of 2 oz copper



135°C/W when mounted on a minimum pad.

2. Pulse Test: Pulse Width < 300 μ s, Duty Cycle < 2.0%

Typical Characteristics

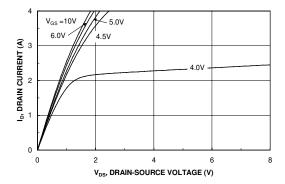


Figure 1. On-Region Characteristics.

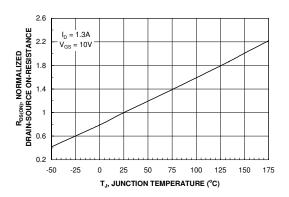


Figure 3. On-Resistance Variation with Temperature.

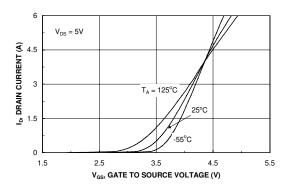


Figure 5. Transfer Characteristics.

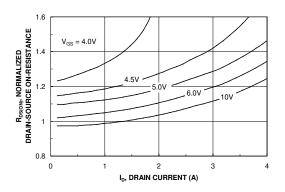


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

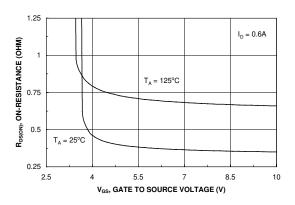


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

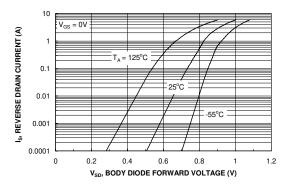
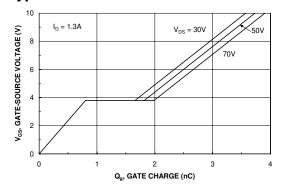


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Characteristics



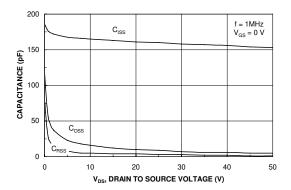


Figure 7. Gate Charge Characteristics.

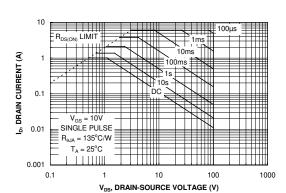


Figure 8. Capacitance Characteristics.

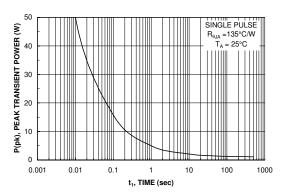


Figure 9. Maximum Safe Operating Area.



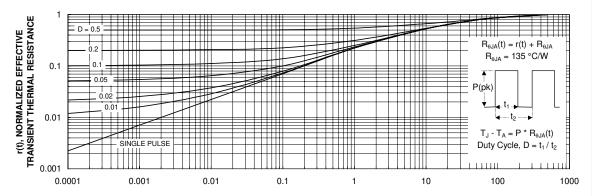


Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1c. Transient thermal response will change depending on the circuit board design.

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Rev. H3